DS05-11045-1E

MEMORY cmos

# 4×1 M×16 BIT SYNCHRONOUS DYNAMIC RAM

MB81F641642C-102/-103/-102L/-103L

CMOS 4-Bank  $\times$  1,048,576-Word  $\times$  16 Bit Synchronous Dynamic Random Access Memory

#### **■** DESCRIPTION

The Fujitsu MB81F641642C is a CMOS Synchronous Dynamic Random Access Memory (SDRAM) containing 67,108,864 memory cells accessible in a 16-bit format. The MB81F641642C features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence. The MB81F641642C SDRAM is designed to reduce the complexity of using a standard dynamic RAM (DRAM) which requires many control signal timing constraints, and may improve data bandwidth of memory as much as 5 times more than a standard DRAM.

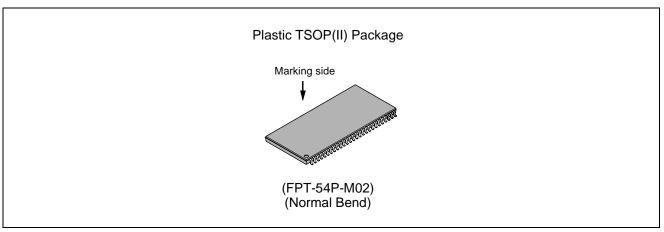
The MB81F641642C is ideally suited for workstations, personal computers, laser printers, high resolution graphic adapters/accelerators and other applications where an extremely large memory and bandwidth are required and where a simple interface is needed.

### **■ PRODUCT LINE & FEATURES**

Parameter		MB81F6	641642C		
Farameter	-102	-102L	-103	-103L	
CL - trcd - trp	2 - 2 - 2	clk min.	3 - 2 - 2	clk min.	
Clock Frequency	100 MF	Hz max.	100 MH	Iz max.	
Burst Mode Cycle Time	10 ns	s min.	10 ns min.		
Access Time From Clock (CL = 3)	6 ns	max.	6 ns max.		
Operating Current (2 banks active)	105 m	A max.	105 m	A max.	
Power Down Mode Current (Icc2P)	2 mA max.	1 mA max.	2 mA max.	1 mA max.	
Self Refresh Current (Icce)	1 mA max.	500 μA max.	1 mA max.	500 μA max.	

- Single +3.3 V Supply ±0.3 V tolerance
- LVTTL compatible I/O
- 4 K refresh cycles every 65.6 ms
- Four bank operation
- Burst read/write operation and burst read/single write operation capability
- Standard and low power versions
- Programmable burst type, burst length, and CAS latency
- Auto-and Self-refresh (every 16 μs)
- CKE power down mode
- Output Enable and Input Data Mask

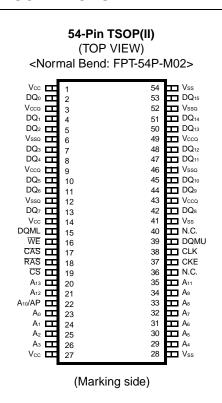
### **■ PACKAGE**



### **Package and Ordering Information**

54-pin plastic (400 mil) TSOP-II, order as MB81F641642C-xxxFN (Std power),
 MB81F641642C-xxxLFN (Low power), MB81F641642C-xxxEFN (Extra power)

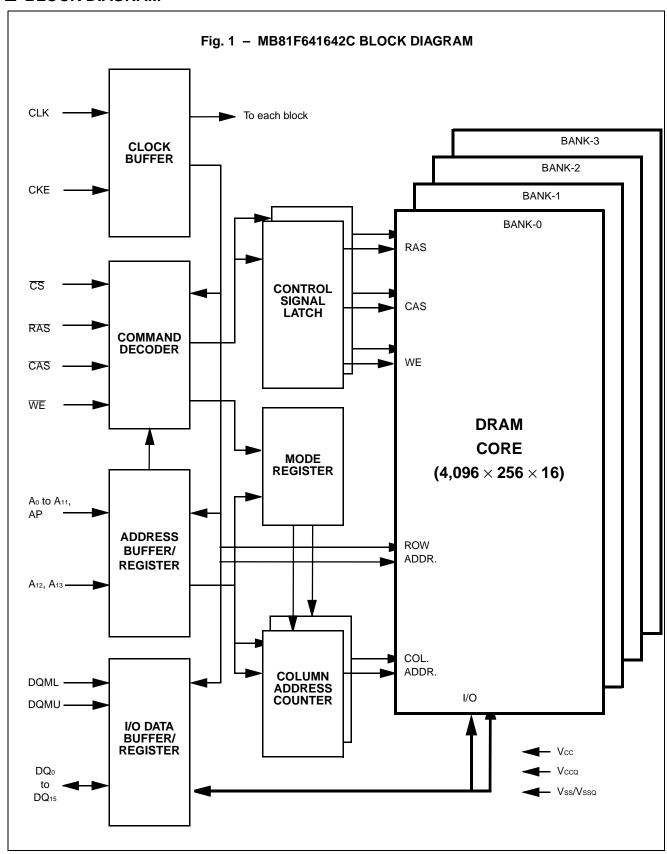
### **■ PIN ASSIGNMENTS AND DESCRIPTIONS**



Pin Number	Symbol	Function
1, 3, 9, 14, 27, 43, 49	Vcc, Vccq	Supply Voltage
2, 4, 5, 7, 8, 10, 11, 13, 42, 44, 45, 47, 48, 50, 51, 53	DQ <sub>0</sub> to DQ <sub>15</sub>	Data I/O
6, 12, 28, 41, 46, 52, 54	Vss, Vssq *	Ground
36, 40	N.C.	No Connection
16	WE	Write Enable
17	CAS	Column Address Strobe
18	RAS	Row Address Strobe
19	CS	Chip Select
20, 21	A <sub>13</sub> (BA <sub>0</sub> ), A <sub>12</sub> (BA <sub>1</sub> )	Bank Select (Bank Address)
22	AP	Auto Precharge Enable
22, 23, 24, 25, 26, 29, 30, 31, 32, 33, 34, 35	Ao to A11	Address Input  • Row: Ao to A <sub>11</sub> • Column: Ao to A <sub>7</sub>
37	CKE	Clock Enable
38	CLK	Clock Input
15, 39	DQML, DQMU	Input Mask/Output Enable

<sup>\*:</sup> These pins are connected internally in the chip.

### **■ BLOCK DIAGRAM**



### **■ FUNCTIONAL TRUTH TABLE** Note 1

### COMMAND TRUTH TABLE Notes 2, 3, and 4

Function	Notos	Symbol	CI	ΚE	CS	RAS	CAS	WE	A <sub>13</sub> ,	<b>A</b> 10	<b>A</b> 11	A <sub>9</sub> to
Function	NOIES	Syllibol	n-1	n	CS	KAS	CAS	VVE	(BA)	(AP)	<b>A</b> 11	Ao
Device Deselect	*5	DESL	Н	Х	Н	Х	Х	Х	Х	Х	Х	X
No Operation	*5	NOP	Н	Х	L	Н	Н	Н	Х	Х	Х	Х
Burst Stop		BST	Н	Х	L	Н	Н	L	Х	Х	Х	Х
Read	*6	READ	Н	Х	L	Н	L	Н	V	L	Х	V
Read with Auto-precharge	*6	READA	Н	Х	L	Н	L	Н	V	Н	Х	V
Write	*6	WRIT	Н	Х	L	Н	L	L	V	L	Х	V
Write with Auto-precharge	*6	WRITA	Н	Х	L	Н	L	L	V	Н	Х	V
Bank Active (RAS)	*7	ACTV	Н	Х	L	L	Н	Н	V	V	V	V
Precharge Single Bank		PRE	Н	Х	L	L	Н	L	V	L	Х	Х
Precharge All Banks		PALL	Н	Х	L	L	Н	L	Х	Н	Х	Х
Mode Register Set	*8, 9	MRS	Н	Х	L	L	L	L	Х	Х	Х	V

**Notes:** \*1. V = Valid, L = Logic Low, H = Logic High, X = either L or H.

- \*2. All commands assumes no CSUS command on previous rising edge of clock.
- \*3. All commands are assumed to be valid state transitions.
- \*4. All inputs are latched on the rising edge of clock.
- \*5. NOP and DESL commands have the same effect on the part.
- \*6. READ, READA, WRIT and WRITA commands should only be issued after the corresponding bank has been activated (ACTV command). Refer to STATE DIAGRAM.
- \*7. ACTV command should only be issued after corresponding bank has been precharged (PRE or PALL command).
- \*8. Required after power up.
- \*9. MRS command should only be issued after all banks have been precharged (PRE or PALL command). Refer to STATE\_DIAGRAM.

### **DQM TRUTH TABLE**

Function	Command	CI	KE	DQML	DQMU
i unction	Command	n-1	n	DQIVIL	DQIVIO
Data Write/Output Enable for Lower Byte	ENBL L	Н	Х	L	Х
Data Write/Output Enable for Upper Byte	ENBL U	Н	Х	Х	L
Data Mask/Output Disable for Lower Byte	MASK L	Н	Х	Н	Х
Data Mask/Output Disable for Upper Byte	MASK U	Н	Х	Х	Н

#### **CKE TRUTH TABLE**

Current	Function N	letes	Cumbal	CI	ΚE	cs	RAS	CAS	WE	A <sub>13</sub> ,	<b>A</b> 10	A <sub>11</sub> , A <sub>9</sub> to	
State	Function r	lotes	Symbol	n-1	n	CS	KAS	CAS	VVE	A <sub>12</sub> (BA)	(AP)	Ao	
Bank Active	Clock Suspend Mode Entry	*1	CSUS	Н	L	Х	Х	Х	Х	Х	Х	Х	
Any (Except Idle)	Clock Suspend Continue	*1		L	L	Х	Х	Х	Х	Х	Х	Х	
Clock Suspend	Clock Suspend Mode Exit			L	Н	Х	Х	Х	Х	Х	Х	Х	
Idle	Auto-refresh Command	*2	REF	Н	Н	L	L	L	Н	Х	Х	Х	
Idle	Self-refresh Entry	*2, 3	SELF	Н	L	L	L	L	Н	Х	Х	Х	
Salf Dafrach	Self-refresh Exit	*4	SELFX	L	Н	L	Н	Н	Н	Х	Х	Х	
Self Refresh	Sell-refresh Exit	4	SELFA	L	Н	Н	Х	Х	Х	Х	Х	Х	
اماله	Down Down Fater	*0	DD	Н	L	L	Н	Н	Н	Х	Х	Х	
Idle	Power Down Entry	*3	PD	Н	L	Н	Х	Х	Х	Х	Х	Х	
Dower Down	Dower Down Evit			L	Н	L	Н	Н	Н	Х	Х	Х	
Power Down	Power Down Exit			L	Н	Н	Х	Х	Χ	Х	Х	Х	

Notes: \*1. The CSUS command requires that at least one bank is active. Refer to STATE DIAGRAM.

- \*2. REF and SELF commands should only be issued after all banks have been precharged (PRE or PALL command). Refer to STATE DIAGRAM.
- \*3. SELF and PD commands should only be issued after the last read data have been appeared on DQ.
- \*4. CKE should be held high within tRC.

### **OPERATION COMMAND TABLE (Applicable to single bank)**

Current State	cs	RAS	CAS	WE	Addr	Command	Function Notes
Idle	Н	Х	Х	Х	Х	DESL	NOP
	L	Н	Н	Н	Х	NOP	NOP
	L	Н	Н	L	Х	BST	NOP
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal *2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal *2
	L	L	Н	Н	BA, RA	ACTV	Bank Active
	L	L	Н	L	BA, AP	PRE/PALL	NOP (PALL may affect other banks.)
	L	L	L	Н	Х	REF/SELF	Auto-refresh or Self-refresh *3
	L	L	L	L	MODE	MRS	Mode Register Set *3, 7 (Idle after trsc)
Bank Active	Н	Х	Х	Х	Х	DESL	NOP
	L	Н	Н	Н	Х	NOP	NOP
	L	Н	Н	L	Х	BST	NOP
	L	Н	L	Н	BA, CA, AP	READ/READA	Begin Read; Determine AP
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Begin Write; Determine AP
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	BA, AP	PRE/PALL	Precharge; Determine Precharge Type (PALL may affect other banks.)
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

Current State	cs	RAS	CAS	WE	Addr	Command	Function Notes
Read	Н	Х	Х	Х	Х	DESL	NOP (Continue Burst to End → Bank Active)
	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End → Bank Active)
	L	Н	Н	L	Х	BST	Burst Stop → Bank Active
	L	Н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, New Read; Determine AP
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Terminate Burst, Start Write; Determine AP
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	BA, AP	PRE/PALL	Terminate Burst, Precharge → Idle; Determine Precharge Type
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal
Write	Н	Х	Х	Х	Х	DESL	NOP (Continue Burst to End → Bank Active)
	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End → Bank Active)
	L	Н	Н	L	Х	BST	Burst Stop → Bank Active
	L	Н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, Start Read; Determine AP
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Terminate Burst, New Write; Determine AP
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	BA, AP	PRE/PALL	Terminate Burst, Precharge → Idle; Determine Precharge Type (PALL may affect other banks.)
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

Current State	cs	RAS	CAS	WE	Addr	Command	Function Notes
Read with Auto- precharge	Н	Х	Х	Х	Х	DESL	NOP (Continue Burst to End $\rightarrow$ Precharge $\rightarrow$ Idle)
precharge	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End $\rightarrow$ Precharge $\rightarrow$ Idle)
	L	Н	Н	L	Х	BST	Illegal
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	ВА	PRE	Illegal *2
	L	L	Н	L	AP	PALL	Illegal
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal
Write with Auto- precharge	Н	х	Х	Х	Х	DESL	NOP (Continue Burst to End $\rightarrow$ Precharge $\rightarrow$ Idle)
precharge	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End $\rightarrow$ Precharge $\rightarrow$ Idle)
	L	Н	Н	L	Х	BST	Illegal
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	ВА	PRE	Illegal *2
	L	L	Н	L	AP	PALL	Illegal
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

Current State	cs	RAS	CAS	WE	Addr	Command	Function	Notes
Precharge	Н	Х	Х	Х	Х	DESL	NOP (Idle after trp)	
	L	Н	Н	Н	Х	NOP	NOP (Idle after t <sub>RP</sub> )	
	L	Н	Н	L	Х	BST	NOP (Idle after t <sub>RP</sub> )	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	NOP (PALL may affect other bank)	*5
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
Bank Activating	Н	Х	Х	Х	Х	DESL	NOP (Bank Active after tRCD)	
Activating	L	Н	Н	Н	Х	NOP	NOP (Bank Active after tRCD)	
	L	Н	Н	L	Х	BST	NOP (Bank Active after tRCD)	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	ВА	PRE	Illegal	*2
	L	L	Н	L	AP	PALL	Illegal	
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

### (Continued)

Current State	cs	RAS	CAS	WE	Addr	Command	Function Notes
Refreshing	Н	Х	Х	Х	Х	DESL	NOP (Idle after trc)
	L	Н	Н	Х	Х	NOP/BST	NOP (Idle after trc)
	L	Н	L	Х	Х	READ/READA/ WRIT/WRITA	Illegal
	L	L	Н	Х	Х	ACTV/ PRE/PALL	Illegal
	L	L	L	Х	Х	REF/SELF/ MRS	Illegal
Mode Register	Н	Х	Х	Х	Х	DESL	NOP (Idle after trsc)
Setting	L	Н	Н	Н	Х	NOP	NOP (Idle after trsc)
	L	Н	Н	L	Х	BST	Illegal
	L	Н	L	х	Х	READ/READA/ WRIT/WRITA	Illegal
	L	L	Х	Х	Х	ACTV/PRE/ PALL/REF/ SELF/MRS	Illegal

### **ABBREVIATIONS:**

RA = Row Address BA = Bank Address CA = Column Address AP = Auto Precharge

### **COMMAND TRUTH TABLE FOR CKE**

Current State	CKE n-1	CKE n	cs	RAS	CAS	WE	Addr	Function Notes
Self- refresh	Н	Х	Х	Х	Х	Х	Х	Invalid
renesii	L	Н	Н	Х	Х	Х	Х	Exit Self-refresh (Self-refresh Recovery $\rightarrow$ Idle after t <sub>RC</sub> )
	L	Н	L	Н	Н	Н	Х	Exit Self-refresh (Self-refresh Recovery → Idle after trc)
	L	Н	L	Н	Н	L	Х	Illegal
	L	Н	L	Н	L	Х	Х	Illegal
	L	Н	L	L	Х	Х	Х	Illegal
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Self-refresh)
Self- refresh	L	Х	Х	Х	Х	Х	Х	Invalid
Recovery	Н	Н	Н	Х	Х	Х	Х	Idle after trc
	Н	Н	L	Н	Н	Н	Х	Idle after trc
	Н	Н	L	Н	Н	L	Х	Illegal
	Н	Н	L	Н	L	Х	Х	Illegal
	Н	Н	L	L	Х	Х	Х	Illegal
	Н	L	Х	Х	Х	Х	Х	Illegal

Current State	CKE n-1	CKE n	cs	RAS	CAS	WE	Addr	Function Notes
Power Down	Н	Х	Χ	Х	Х	Х	Х	Invalid
Down		Н	Н	Х	Х	Х	Х	Exit Power Down Mode → Idle
	L	П	L	Н	Н	Н	Х	Exit Power Down Wode → Idle
	L	L	Χ	Х	Х	Х	Х	NOP (Maintain Power Down Mode)
	L	Н	L	L	Х	Х	Х	Illegal
	L	Н	L	Н	L	Х	Х	Illegal
	L	Н	L	Н	Н	L	Х	Illegal
All Banks	Н	Н	Н	Х	Х	Х		Refer to the Operation Command Table.
Idle	Н	Н	L	Н	Х	Х		Refer to the Operation Command Table.
	Н	Н	L	L	Н	Х		Refer to the Operation Command Table.
	Н	Н	L	L	L	Н	Х	Auto-refresh
	Н	Н	L	L	L	L	MODE	Refer to the Operation Command Table.
	Н	L	Н	Х	Х	Х	Х	Power Down *6
	Н	L	L	Н	Н	Н	Х	Power Down *6
	Н	L	L	Н	Н	L		Illegal
	Н	L	L	Н	L	Х	Х	Illegal
	Н	L	L	L	Н	Х	Х	Illegal
	Н	L	L	L	L	Н	Х	Self-refresh *6
	Н	L	L	L	L	L	Х	Illegal
	L	Х	Х	Х	Х	Х	Х	Invalid

### (Continued)

Current State	CKE n-1	CKE n	CS	RAS	CAS	WE	Addr	Function Notes	
Bank Active Bank	Н	Н	Х	Х	Х	Х	Х	Refer to the Operation Command Table.	
Activating Read/Write	Н	L	Х	х	Х	Х	Х	Begin Clock Suspend next cycle	
Read with Auto- precharge/ Write with	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend next cycle	
Auto- precharge	L	L	Х	Х	Х	Х	Х	Maintain Clock Suspend	
Clock Suspend	Н	Х	Х	Х	Х	Х	Х	Invalid	
Suspend	L	Н	X	Х	Х	Χ	Х	Exit Clock Suspend next cycle	
	L	L	Χ	Х	Х	Χ	Х	Maintain Clock Suspend	
Any State Other Than	L	Х	Χ	Х	Х	Χ	Х	Invalid	
Listed Above	Н	Н	Х	Х	Х	Х	Х	Refer to the Operation Command Table	
, 1,50 40	Н	L	Х	Х	Х	Х	Х	Illegal	

**Notes:** \*1. All entries assume the CKE was High during the proceeding clock cycle and the current clock cycle. Illegal means don't used command. If used, power up sequence be asserted after power shut down.

- \*2. Illegal to bank in specified state; entry may be legal in the bank specified by BA, depending on the state of that bank.
- \*3. Illegal if any bank is not idle.
- \*4. Must satisfy bus contention, bus turn around, and/or write recovery requirements.
- \*5. NOP to bank precharging or in idle state.

  May precharge bank spesified by BA (and AP).
- \*6. SELF command should only be issued after the last read data have been appeared on DQ.
- \*7. MRS command should only be issued on condition that all DQ are in Hi-Z.

#### **■ FUNCTIONAL DESCRIPTION**

#### **SDRAM BASIC FUNCTION**

Three major differences between this SDRAM and conventional DRAMs are: synchronized operation, burst mode, and mode register.

The **synchronized operation** is the fundamental difference. An SDRAM uses a clock input for the synchronization, where the DRAM is basically asynchronous memory although it has been using two clocks, RAS and CAS. Each operation of DRAM is determined by their timing phase differences while each operation of SDRAM is determined by commands and all operations are referenced to a positive clock edge. Fig 3 shows the basic timing diagram differences between SDRAMs and DRAMs.

The **burst mode** is a very high speed access mode utilizing an internal column address generator. Once a column addresses for the first access is set, following addresses are automatically generated by the internal column address counter.

The **mode register** is to justify the SDRAM operation and function into desired system conditions. MODE REGISTER TABLE shows how SDRAM can be configured for system requirement by mode register programming.

### **CLOCK (CLK) and CLOCK ENABLE (CKE)**

All input and output signals of SDRAM use register type buffers. A CLK is used as a trigger for the register and internal burst counter increment. All inputs are latched by a positive edge of CLK. All outputs are validated by the CLK. CKE is a high active clock enable signal. When CKE = Low is latched at a clock input during active cycle, the next clock will be internally masked. During idle state (all banks have been precharged), the Power Down mode (standby) is entered with CKE = Low and this will make extremely low standby current.

### CHIP SELECT (CS)

CS enables all commands inputs, RAS, CAS, and WE, and address input. When CS is High, command signals are negated but internal operation such as burst cycle will not be suspended. If such a control isn't needed, CS can be tied to ground level.

### COMMAND INPUT (RAS, CAS and WE)

Unlike a conventional DRAM, RAS, CAS, and WE do not directly imply SDRAM operation, such as Row address strobe by RAS. Instead, each combination of RAS, CAS, and WE input in conjunction with CS input at a rising edge of the CLK determines SDRAM operation. Refer to FUNCTIONAL TRUTH TABLE in page 5.

### ADDRESS INPUT (Ao to A11)

Address input selects an arbitrary location of a total of 1,048,576 words of each memory cell matrix. A total of fourteen address input signals are required to decode such a matrix. SDRAM adopts an address multiplexer in order to reduce the pin count of the address line. At a Bank Active command (ACTV), twelve Row addresses are initially latched and the remainder of eight Column addresses are then latched by a Column address strobe command of either a Read command (READ or READA) or Write command (WRIT or WRITA).

#### BANK SELECT (A13, A12)

This SDRAM has four banks and each bank is organized as 1 M words by 16-bit. Bank selection by A<sub>13</sub>, A<sub>12</sub> occurs at Bank Active command (ACTV) followed by read (READ or READA), write (WRIT or WRITA), and precharge command (PRE).

### DATA INPUTS AND OUTPUTS (DQ<sub>0</sub> to DQ<sub>15</sub>)

Input data is latched and written into the memory at the clock following the write command input. Data output is obtained by the following conditions followed by a read command input:

trac ; from the bank active command when trcd (min) is satisfied. (This parameter is reference only.)

tcac; from the read command when tRCD is greater than tRCD (min). (This parameter is reference only.)

tac ; from the clock edge after trac and tcac.

The polarity of the output data is identical to that of the input. Data is valid between access time (determined by the three conditions above) and the next positive clock edge (toh).

### DATA I/O MASK (DQML/DQMU)

DQML and DQMU are an active high enable input and has an output disable and input mask function. During burst cycle and when DQML/DQMU = High is latched by a clock, input is masked at the same clock and output will be masked at the second clock later while internal burst counter will increment by one or will go to the next stage depending on burst type.

#### **BURST MODE OPERATION AND BURST TYPE**

The burst mode provides faster memory access. The burst mode is implemented by keeping the same Row address and by automatic strobing column address. Access time and cycle time of Burst mode is specified as tac and tok, respectively. The internal column address counter operation is determined by a mode register which defines burst type and burst count length of 1, 2, 4 or 8 bits of boundary. In order to terminate or to move from the current burst mode to the next stage while the remaining burst count is more than 1, the following combinations will be required:

Current Stage	Next Stage	N	Method (Assert the following command)			
Burst Read	Burst Read		Read Command			
D. aut D. aut	Burst Write	1st Step	Mask Command (Normally 3 clock cycles)			
Burst Read	buist write	2nd Step Write Command after lowb	Write Command after lowp			
Burst Write	Burst Write		Write Command			
Burst Write	Burst Read		Read Command			
Burst Read	Precharge		Precharge Command			
Burst Write	Precharge		Precharge Command			

The burst type can be selected either sequential or interleave mode if burst length is 2, 4 or 8. The sequential mode is an incremental decoding scheme within a boundary address to be determined by count length, it assigns +1 to the previous (or initial) address until reaching the end of boundary address and then wraps round to least significant address (= 0). The interleave mode is a scrambled decoding scheme for A<sub>0</sub> and A<sub>2</sub>. If the first access of column address is even (0), the next address will be odd (1), or vice-versa.

#### (Continued)

When the full burst operation is executed at single write mode, Auto-precharge command is valid only at write operation.

The burst type can be selected either sequential or interleave mode. But only the sequential mode is usable to the full column burst. The sequential mode is an incremental decoding scheme within a boundary address to be determined by burst length, it assigns +1 to the previous (or initial) address until reaching the end of boundary address and then wraps round to least significant address (= 0).

Burst Length	Starting Column Address A <sub>2</sub> A <sub>1</sub> A <sub>0</sub>	Sequential Mode	Interleave
2	X X 0	0 – 1	0 – 1
2	X X 1	1 – 0	1 – 0
	X 0 0	0-1-2-3	0-1-2-3
4	X 0 1	1-2-3-0	1-0-3-2
4	X 1 0	2-3-0-1	2-3-0-1
	X 1 1	3-0-1-2	3-2-1-0
	0 0 0	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7
	0 0 1	1-2-3-4-5-6-7-0	1-0-3-2-5-4-7-6
	0 1 0	2-3-4-5-6-7-0-1	2-3-0-1-6-7-4-5
8	0 1 1	3-4-5-6-7-0-1-2	3-2-1-0-7-6-5-4
0	1 0 0	4-5-6-7-0-1-2-3	4-5-6-7-0-1-2-3
	1 0 1	5-6-7-0-1-2-3-4	5-4-7-6-1-0-3-2
	1 1 0	6-7-0-1-2-3-4-5	6-7-4-5-2-3-0-1
	1 1 1	7-0-1-2-3-4-5-6	7-6-5-4-3-2-1-0

#### FULL COLUMN BURST AND BURST STOP COMMAND (BST)

The full column burst is an option of burst length and available only at sequential mode of burst type. This full column burst mode is repeatedly access to the same column. If burst mode reaches end of column address, then it wraps round to first column address (= 0) and continues to count until interrupted by the news read (READ) /write (WRIT), precharge (PRE), or burst stop (BST) command. The selection of Auto-precharge option is illegal during the full column burst operation except write command at BURST READ & SINGLE WRITE mode.

The BST command is applicable to terminate the burst operation. If the BST command is asserted during the burst mode, its operation is terminated immediately and the internal state moves to Bank Active.

When read mode is interrupted by BST command, the output will be in High-Z.

For the detail rule, please refer to Timing Diagram-8.

When write mode is interrupted by BST command, the data to be applied at the same time with BST command will be ignored.

#### **BURST READ & SINGLE WRITE**

The burst read and single write mode provides single word write operation regardless of its burst length. In this mode, burst read operation does not be affected by this mode.

### PRECHARGE AND PRECHARGE OPTION (PRE, PALL)

SDRAM memory core is the same as conventional DRAMs', requiring precharge and refresh operations. Precharge rewrites the bit line and to reset the internal Row address line and is executed by the Precharge command (PRE). With the Precharge command, SDRAM will automatically be in standby state after precharge time (trp).

The precharged bank is selected by combination of AP and A<sub>13</sub>, A<sub>12</sub> when Precharge command is asserted. If AP = High, all banks are precharged regardless of A<sub>13</sub>, A<sub>12</sub> (PALL). If AP = Low, a bank to be selected by A<sub>13</sub>, A<sub>12</sub> is precharged (PRE).

The auto-precharge enters precharge mode at the end of burst mode of read or write without Precharge command assertion.

This auto precharge is entered by AP = High when a read or write command is asserted. Refer to FUNCTIONAL TRUTH TABLE.

### **AUTO-REFRESH (REF)**

Auto-refresh uses the internal refresh address counter. The SDRAM Auto-refresh command (REF) generates Precharge command internally. All banks of SDRAM should be precharged prior to the Auto-refresh command. The Auto-refresh command should also be asserted every 16  $\mu s$  or a total 4096 refresh commands within a 65.6 ms period.

### **SELF-REFRESH ENTRY (SELF)**

Self-refresh function provides automatic refresh by an internal timer as well as Auto-refresh and will continue the refresh function until cancelled by SELFX.

The Self-refresh is entered by applying an Auto-refresh command in conjunction with CKE = Low (SELF). Once SDRAM enters the self-refresh mode, all inputs except for CKE will be "don't care" (either logic high or low level state) and outputs will be in a High-Z state. During a self-refresh mode, CKE = Low should be maintained. SELF command should only be issued after last read data has been appeared on DQ.

**Note:** When the burst refresh method is used, a total of 4096 auto-refresh commands within 4 ms must be asserted prior to the self-refresh mode entry.

#### SELF-REFRESH EXIT (SELFX)

To exit self-refresh mode, apply minimum tPDE after CKE brought high, and then the NOP command (NOP) or the Deselect command (DESL) should be asserted within one tRC period. CKE should be held High within one tRC period after tPDE. Refer to Timing Diagram for the detail.

It is recommended to assert an Auto-refresh command just after the tRC period to avoid the violation of refresh period.

**Note:** When the burst refresh method is used, a total of 4096 auto-refresh commands within 4 ms must be asserted after the self-refresh exit.

#### MODE REGISTER SET (MRS)

The mode register of SDRAM provides a variety of different operations. The register consists of four operation fields; Burst Length, Burst Type, CAS latency, and Operation Code. Refer to MODE REGISTER TABLE in page 33.

The mode register can be programmed by the Mode Register Set command (MRS). Each field is set by the address line. Once a mode register is programmed, the contents of the register will be held until re-programmed by another MRS command (or part loses power). MRS command should only be issued on condition that all DQ is in Hi-Z.

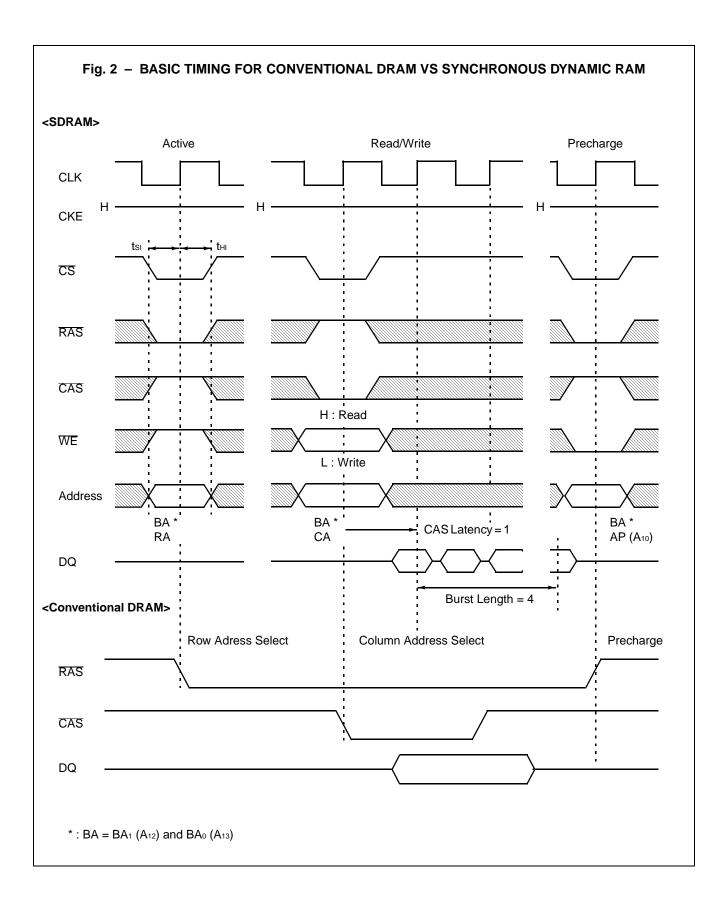
The condition of the mode register is undefined after the power-up stage. It is required to set each field after initialization of SDRAM. Refer to POWER-UP INITIALIZATION below.

### **POWER-UP INITIALIZATION**

The SDRAM internal condition after power-up will be undefined. It is required to follow the following Power On Sequence to execute read or write operation.

- 1. Apply power and start clock. Attempt to maintain either NOP or DESL command at the input.
- 2. Maintain stable power, stable clock, and NOP condition for a minimum of 200  $\mu s$ .
- 3. Precharge all banks by Precharge (PRE) or Precharge All command (PALL).
- 4. Assert minimum of 8 Auto-refresh command (REF).
- 5. Program the mode register by Mode Register Set command (MRS).

In addition, it is recommended DQM and CKE to track  $V_{CC}$  to insure that output is High-Z state. The Mode Register Set command (MRS) can be set before 8 Auto-refresh command (REF).



### MINIMUM CLOCK LATENCY OR DELAY TIME FOR 1 BANK OPERATION

Second command (same bank)  First command	MRS	ACTV	READ	READA	WRIT	WRITA	PRE	PALL	REF	SELF
MRS	<b>t</b> RSC	<b>t</b> RSC					trsc	trsc	<b>t</b> RSC	<b>t</b> rsc
ACTV			trcd	*4 <b>t</b> RCD	trcd	*4 <b>t</b> RCD	<b>t</b> ras	tras		
READ			1	1	*1 4	*1 4	1	1		
READA	BL *2 + t <sub>RP</sub>	BL *2 + t <sub>RP</sub>							BL *2 + t <sub>RP</sub>	BL + t <sub>RP</sub>
WRIT			<b>t</b> wr	twr	1	1	<b>t</b> dpl	<b>t</b> dpl		
WRITA	<b>t</b> dal	<b>t</b> dal							<b>t</b> dal	<b>t</b> dal
PRE	*3 <b>t</b> RP	*3 <b>t</b> RP					<b>t</b> RP	<b>t</b> RP	*3 <b>t</b> RP	*3 <b>t</b> RP
PALL	*3 <b>t</b> RP	*3 <b>t</b> RP					<b>t</b> RP	<b>t</b> RP	*3 <b>t</b> RP	*3 t <sub>RP</sub>
REF	trc	<b>t</b> RC					<b>t</b> RC	<b>t</b> RC	<b>t</b> RC	<b>t</b> RC
SELFX	trc	<b>t</b> rc							trc	<b>t</b> rc

Notes: \*1. Assume no I/O conflict.

- \*2. If  $t_{RP} \le t_{CK}$ , minimum latency is a sum of BL + CL.
- \*3. Assume output is in High-Z state.
- \*4. Assume tras is satisfied.

Illegal Command
-----------------

#### MINIMUM CLOCK LATENCY OR DELAY TIME FOR MULTI BANK OPERATION

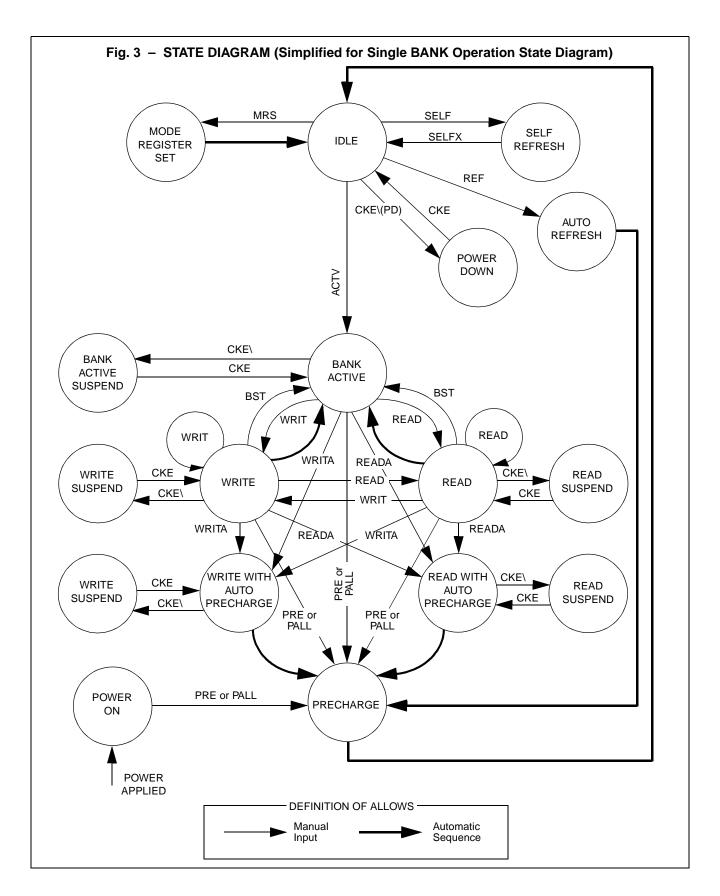
Second command (other bank)  First command	MRS	ACTV	READ	READA	WRIT	WRITA	PRE	PALL	REF	SELF
MRS	trsc	<b>t</b> rsc					trsc	trsc	trsc	trsc
ACTV		*1 <b>t</b> RRD	*2 1	*2 1	*2 1	*2 1	*7 1	*2 <b>t</b> ras		
READ		*1 1	1	1	*2 *3	*2 *3	*7 1	*8 1		
READA *9	*1 *4 BL+ t <sub>RP</sub>	*1 1	1	1	*2 *3	*2 *3	1		*1 BL+ t <sub>RP</sub>	*1 *4 BL+ t <sub>RP</sub>
WRIT		*1 <b>1</b>	*2 1	*2 <b>1</b>	*2 <b>1</b>	*2 <b>1</b>	*7 1	*8 1		
WRITA *9	*1 *4 BL+ t <sub>RP</sub>	*1 <b>1</b>	*2 1	*2 1	*2 <b>1</b>	*2 <b>1</b>	1		BL+ t <sub>RP</sub>	BL+ t <sub>RP</sub>
PRE	*1 <b>t</b> RP	*1 <b>1</b>	*2 1	*2 <b>1</b>	*2 <b>1</b>	*2 <b>1</b>	1	*2 <b>t</b> ras	*1 <b>t</b> RP	*1 <b>t</b> RP
PALL *5	<b>t</b> RP	<b>t</b> RP					1	1	*1 *6 <b>t</b> RP	*1 *6 <b>t</b> RP
REF	<b>t</b> RC	<b>t</b> RC					<b>t</b> RC	<b>t</b> RC	<b>t</b> RC	<b>t</b> RC
SELFX	<b>t</b> rc	trc							trc	<b>t</b> rc

Notes: \*1. Assume other banks is in idle state.

- \*2. Assume other banks is in active state.
- \*3. Assume no I/O conflict.
- \*4. If  $t_{RP} \le t_{CK}$ , minimum latency is a sum of BL + CL.
- \*5. Assume PALL command dose not affect any operation on other banks.
- \*6. Assume output is in High-Z sate.
- \*7. Assume tras of other banks is satisfied.
- \*8. Assume tras (ACTV to PALL) is satisfied.
- \*9. If other banks should be interrupted, tras of own bank is satisfied.

Illegal Com	mand
-------------	------

22



### ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Value	Unit
Voltage of Vcc Supply Relative to Vss	Vcc, Vcca	-0.5 to +4.6	V
Voltage at Any Pin Relative to Vss	VIN, VOUT	-0.5 to +4.6	V
Short Circuit Output Current	Іоит	-50 to +50	mA
Power Dissipation	Po	1.0	W
Storage Temperature	Тѕтс	-55 to +125	°C

**WARNING:** Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

### **■ RECOMMENDED OPERATING CONDITIONS**

### (Referenced to Vss)

Parameter	Notes	Symbol	Min.	Тур.	Max.	Unit
Supply Voltage		Vcc, Vccq	3.0	3.3	3.6	V
Supply Voltage		Vss, Vssq	0	0	0	V
Input High Voltage	*1	VIH	2.0	_	Vcc + 0.5	V
Input Low Voltage	*2	VIL	-0.5	_	0.8	V
Ambient Temperature		ТА	0	_	+70	°C

**Notes:** \*1. Overshoot limit:  $V_{IH}$  (max) =  $V_{CC}$  +1.5 V with a pulsewidth  $\leq 5$  ns.

\*2. Undershoot limit:  $V_{\perp}$  (min) = -1.5 V with a pulsewidth  $\leq 5$  ns.

**WARNING:** Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representative beforehand.

#### **■ CAPACITANCE**

 $(T_A = 25^{\circ}C, f = 1 \text{ MHz})$ 

Parameter	Symbol	Min.	Тур.	Max.	Unit
Input Capacitance, Except for CLK	CIN1	2.5	_	5.0	pF
Input Capacitance for CLK	C <sub>IN2</sub>	2.5	_	4.0	pF
I/O Capacitance	C <sub>I/O</sub>	4.0	_	6.5	pF

### **■ DC CHARACTERISTICS**

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

Par	rameter	Symbol	Condition	Va	lue	Unit
Pai	Parameter		Symbol		Max.	Unit
Output High Voltage	)	Voh(DC)	Iон = −2 mA	2.4	_	V
Output Low Voltage		Vol(DC)	IoL = 2 mA	_	0.4	V
Input Leakage Curre	ent (Any Input)	lu	$0 \text{ V} \le \text{Vin} \le \text{Vcc};$ All other pins not under test = $0 \text{ V}$	-10	10	μА
Output Leakage Cu	rrent	ILO	0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub> ; Data out disabled	-10	10	μΑ
	MB81F641642C -102/102L/-103/103L	Icc1s	Burst: Length = 4 tRC = min for $BL = 4tCK = minOne bank activeOutputs openAddresses changed up to3-times during tRC (min)0 \ V \le V_{IN} \le V_{CC}$	_	105	mA
Operating Current (Average Power Supply Current)	MB81F641642C -102/-102L/-103/103L	Icc1D	Burst: Length = 4 (each Bank) $t_{RC}$ = min for BL = 4 (each Bank) $t_{CK}$ = min 2 banks active Outputs open Addresses changed up to 3-times during $t_{RC}$ (min) $0 \ V \le V_{IN} \le V_{CC}$	_	Max.  — 0.4  10	mA
	MB81F641642C -102/103		CKE = V <sub>I</sub> L All banks idle	_	2	A
	MB81F641642C -102L/103L	- ICC2P	$tck = min$ Power down mode $0 \ V \le V_{IN} \le V_{CC}$	_	105 190 2 1 1 0.5	mA
	MB81F641642C -102/-103		CKE = V <sub>I</sub> L All banks idle	_	1	
Precharge	MB81F641642C -102L/103L	ICC2PS	CLK = H  or  L Power down mode $0 \text{ V} \le V_{IN} \le V_{CC}$	_	Max.  0.4  10  105  190  2  1  1  0.5	mA
Standby Current (Power Supply Current)		Ісс2н	CKE = $V_{IH}$ All banks idle, $t_{CK}$ = min NOP commands only, Input signals (except to CMD) are changed one time during 3 clock cycles $0 \text{ V} \leq V_{IN} \leq V_{CC}$	_		mA
		Icc2ns	$CKE = V_{IH}$ All banks idle $CLK = H \text{ or } L$ Input signal are stable $0 \text{ V} \le V_{IN} \le V_{CC}$	_		mA

Parameter		Cumbal	Condition	Va	Unit	
Par	ameter	Symbol	Condition	Min.	Max.	Unit
	MB81F641642C -102/-103	Іссзр	CKE = V <sub>IL</sub> Any bank active	_	2	mA
	MB81F641642C -102L/103L	ICC3P	$t_{CK} = min$ 0 $V \le V_{IN} \le V_{CC}$	_	1	
	MB81F641642C -102/-103	Іссзря	CKE = V <sub>I</sub> L Any bank active	_	1	mA
A ativa Ctandhu	MB81F641642C -102L/103L	1003PS	CLK = H  or  L $0 \text{ V} \le V_{IN} \le V_{CC}$	_	0.5	
Active Standby Current (Power Supply Current)		Іссзи	CKE = V <sub>IH</sub> Any bank active tcκ = min NOP commands only, Input signals (except to CMD) are changed one time during 3 clock cycles 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_	<ul><li>— 0.5</li><li>— 25</li><li>— 2</li></ul>	mA
		Іссзиѕ	CKE = V <sub>IH</sub> Any bank active CLK = H or L 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_		mA
Burst mode Current (Average Power Sup	oply Current)	Icc4	tck = min Burst Length = 4 Outputs open Multiple-banks active Gapless data 0 V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>	_	85	mA
Refresh Current #1 (Average Power Sup	oply Current)	lcc5	Auto-refresh; tck = min tRc = min $0 \ V \le Vin \le Vcc$	_	240	mA
Refresh Current #2 (Average Power	MB81F641642C -102/103	Icc <sub>6</sub>	Self-refresh; tcк = min	_	1	mA
Supply Current)	MB81F641642C -102L/103L	ICCb	$  CKE \le 0.2 \ V                                  $	_	0.5	

### **■ AC CHARACTERISTICS**

(At recommended operating conditions unless otherwise noted.) Notes 2, 3, 4

Dayamatan Natas	Natas	Symbol	MB81F641642C-102/-102L		MB81F641642C-103/-103L		11:4
Parameter Notes	i		Min.	Max.	Min.	Max.	- Unit
Clock Period	CL = 2	<b>t</b> CK2	10	10	15		ns
	CL = 3	<b>t</b> cкз	10		10	_	ns
Clock High Time		<b>t</b> cH	3	_	3	_	ns
Clock Low Time		<b>t</b> cL	3	_	3	_	ns
Input Setup Time		<b>t</b> sı	2	_	2	_	ns
Input Hold Time		tнı	1	_	1	_	ns
Access Time from Clock *5, 6 (tck = min)	CL = 2	<b>t</b> AC2	_	6	_	8	ns
	CL = 3	<b>t</b> AC3		6		6	ns
Output in Low-Z *7		<b>t</b> LZ	0	_	0	_	ns
Output in High-Z *7	CL = 2	<b>t</b> HZ2	3	6	3	8	ns
	CL = 3	<b>t</b> HZ3		6		6	ns
Output Hold Time *7		tон	3	_	3	_	ns
Time between Refresh		<b>t</b> REF	_	65.6	_	65.6	ms
Transition Time		t⊤	0.5	2	0.5	2	ns
CKE Setup Time for Power Down Exit Time		tcksp	3		3		ns

### **BASE VALUES FOR CLOCK COUNT/LATENCY**

Doromotor Notes	6.	Cumbal	MB81F641642C-102/-102L		MB81F641642C-103/-103L		l lni4
Parameter Notes		Symbol	Min.	Max.	Min.	Max.	Unit
RAS Cycle Time *8		<b>t</b> <sub>RC</sub>	70	_	70	_	ns
RAS Precharge Time		<b>t</b> RP	20	_	20	_	ns
RAS Active Time		tras	50	110000	50	110000	ns
RAS to CAS Delay Time *9		trcd	20	_	20	_	ns
Write Recovery Time		twr	10	_	10	_	ns
RAS to RAS Bank Active Delay Time		<b>t</b> rrd	20	_	20	_	ns
Data-in to Precharge Lead Time		<b>t</b> DPL	10	_	10	_	ns
Data-in to Active/Refresh Command Period	CL=2	<b>t</b> DAL2	1 cyc + trp	_	1 cyc + trp	_	ns
	CL=3	<b>t</b> DAL3	2 cyc + t <sub>RP</sub>	_	2 cyc + t <sub>RP</sub>	_	ns
Mode Resister Set Cycle Time		trsc	20	_	20	_	ns

### **CLOCK COUNT FORMULA** Note 13

 $\begin{array}{ccc} \text{Clock} \geq & \frac{\text{Base Value}}{\text{Clock Period}} & \text{(Round off a whole number)} \end{array}$ 

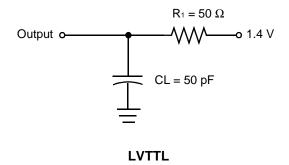
#### **LATENCY - FIXED VALUES**

(The latency values on these parameters are fixed regardless of clock period.)

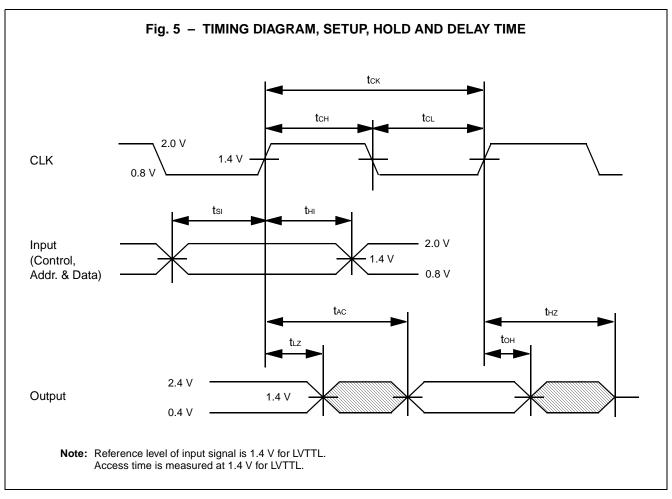
Parameter	Notes	Symbol	MB81F641642C-102/-102L	MB81F641642C-103/-103L	Unit
CKE to Clock Disable		Іске	1	1	cycle
DQM to Output in High-Z		logz	2	2	cycle
DQM to Input Data Delay		IDQD	0	0	cycle
Last Output to Write Command Delay		lowd	2	2	cycle
Write Command to Input Data Delay		lowo	0	0	cycle
Precharge to Output in High-Z Delay	CL = 2	Iron2	2	2	cycle
	CL = 3	Іконз	3	3	cycle
Burst Stop Command to Output in High-Z Delay	CL = 2	I <sub>BSH2</sub>	2	2	cycle
	CL = 3	Івѕнз	3	3	cycle
CAS to CAS Delay (min)		Iccd	1	1	cycle
CAS Bank Delay (min)		Ісво	1	1	cycle

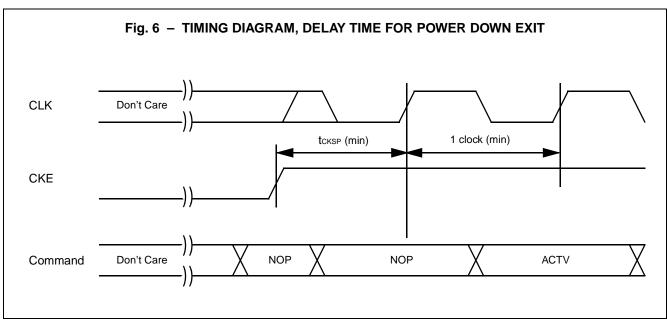
- **Notes:** \*1. Icc depends on the output termination or load conditions, clock cycle rate, signal clocking rate; the specified values are obtained with the output open and no termination register.
  - \*2. An initial pause (DESL or NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
  - \*3. AC characteristics assume  $t_T = 1$  ns and 50 pF of capacitive load.
  - \*4. 1.4 V is the reference level for measuring timing of input signals. Transition times are measured between V<sub>IH</sub> (min) and V<sub>IL</sub> (max). (See Fig. 5)
  - \*5. Maximum value of CL = 2 depends on tck.
  - \*6. tac also specifies the access time at burst mode except for first access.
  - \*7. Specified where output buffer is no longer driven. toH, tLz, and tHz define the times at which the output level achieves ±200 mV.
  - \*8. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
  - \*9. Operation within the trop (min) ensures that access time is determined by trop (min) + trop (max); If trop is greater than the specified trop (min), access time is determined by trop.
  - \*10. All base values are measured from the clock edge at the command input to the clock edge for the next command input. All clock counts are calculated by a simple formula: clock count equals base value divided by clock period (round off to a whole number).

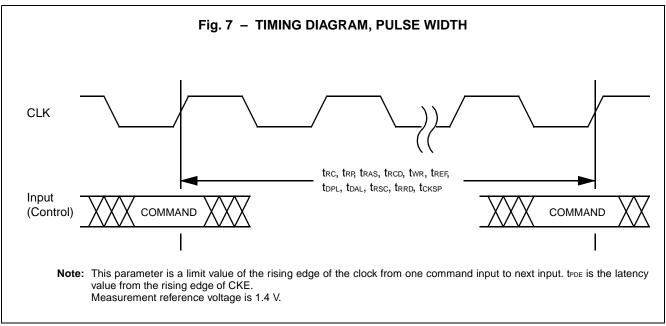
Fig. 4 - EXAMPLE OF AC TEST LOAD CIRCUIT

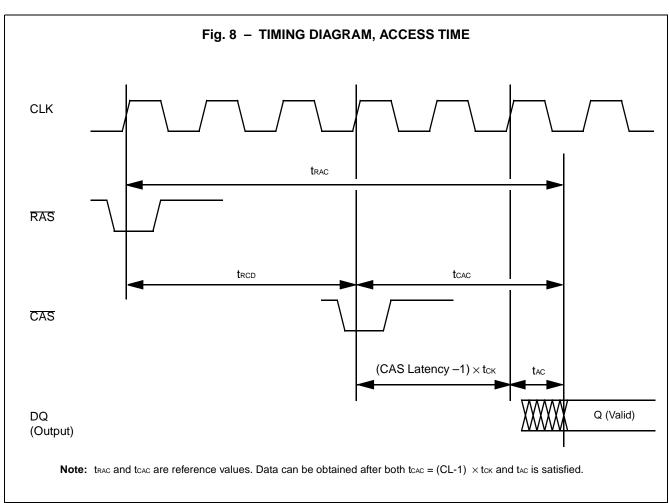


Note: AC characteristics are measured in this condition. This load circuits are not applicable for VoH and VoL.

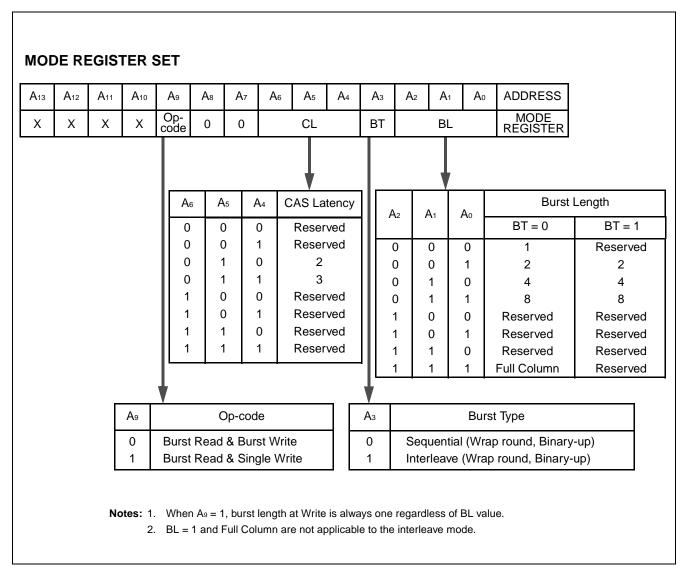


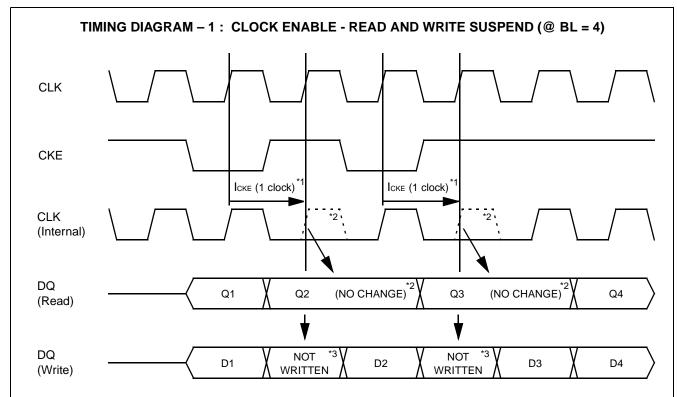






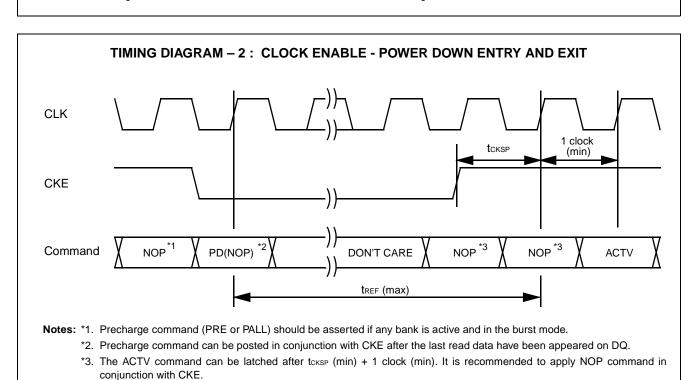
### **■ MODE REGISTER TABLE**



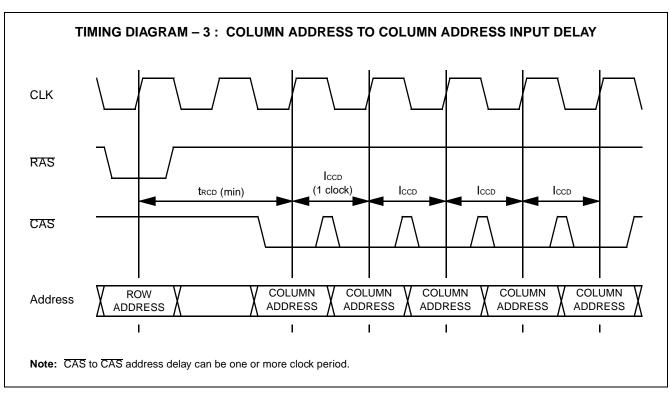


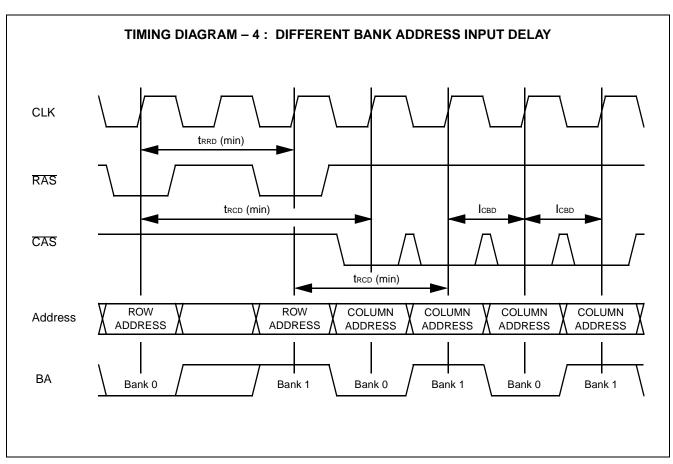
Notes: \*1. The latency of CKE (ICKE) is one clock.

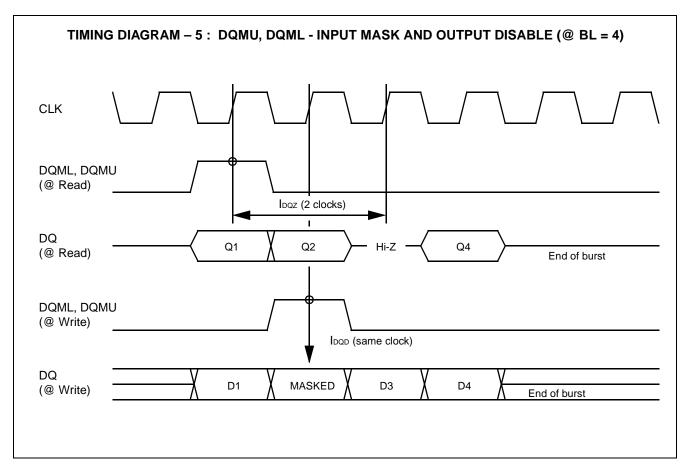
- \*2. During read mode, burst counter will not be incremented/decremented at the next clock of CSUS command. Output remain the same data.
- \*3. During the write mode, data at the next clock of CSUS command is ignored.

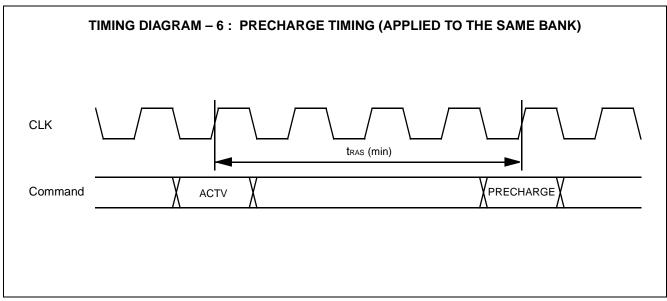


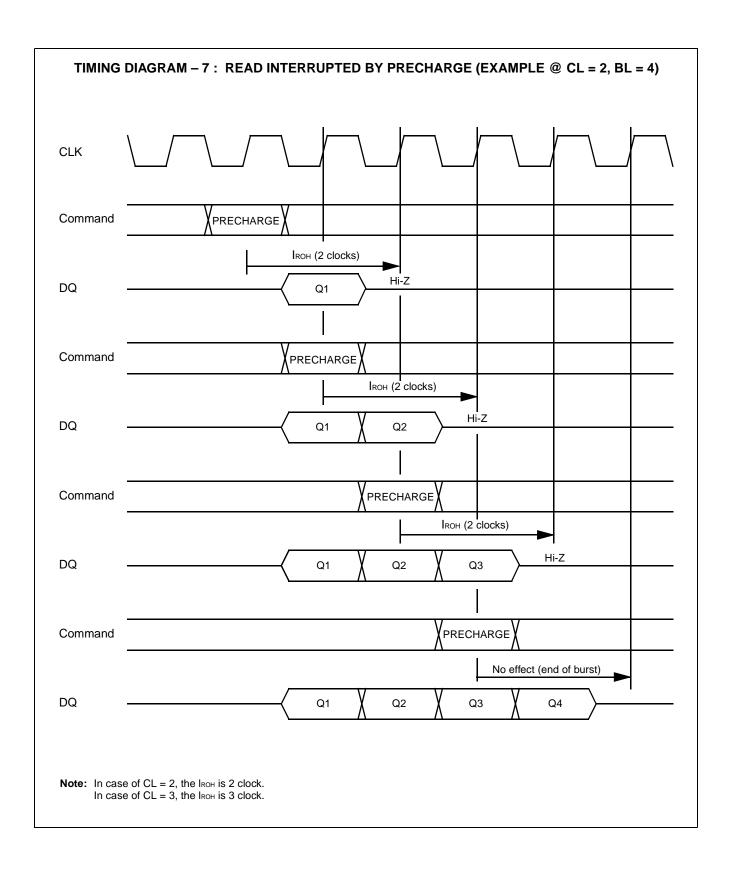
34

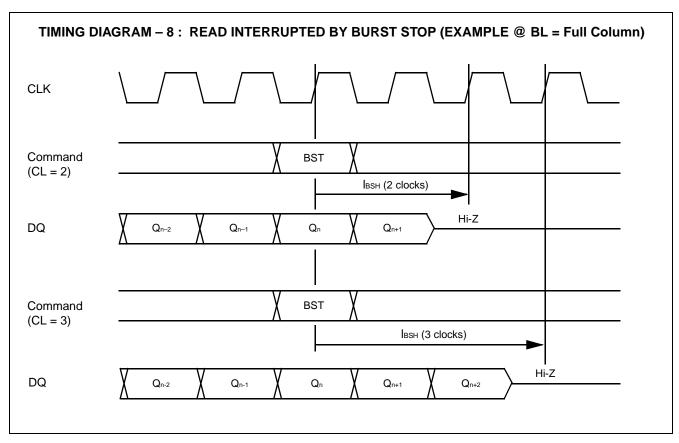


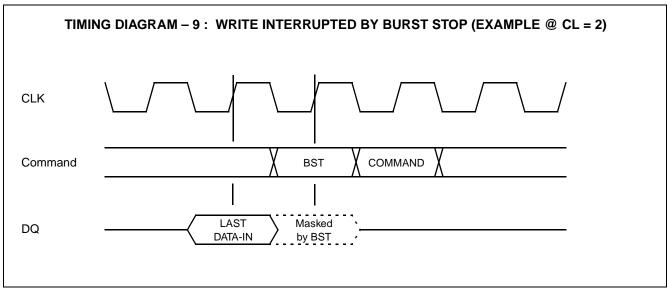


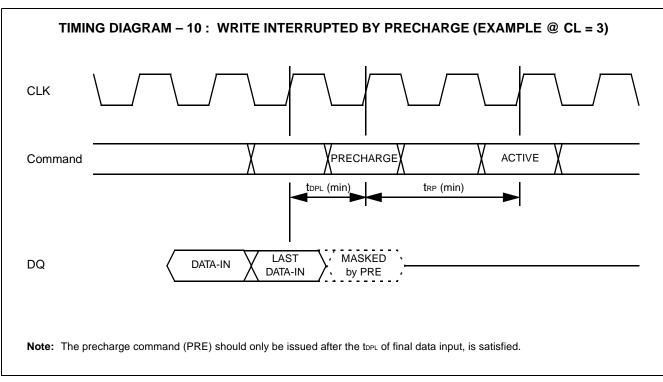


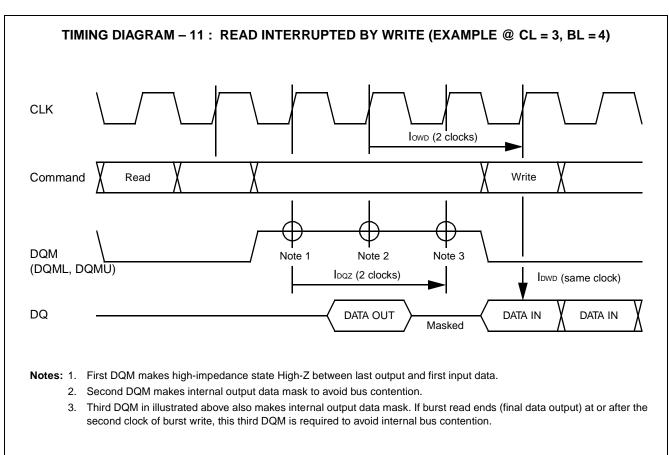


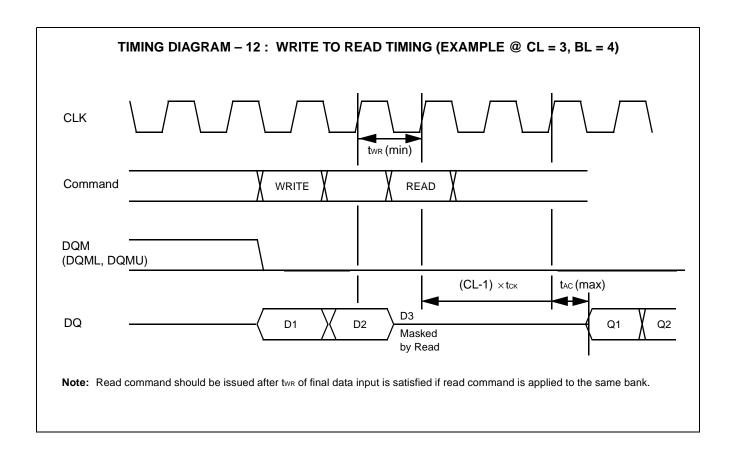


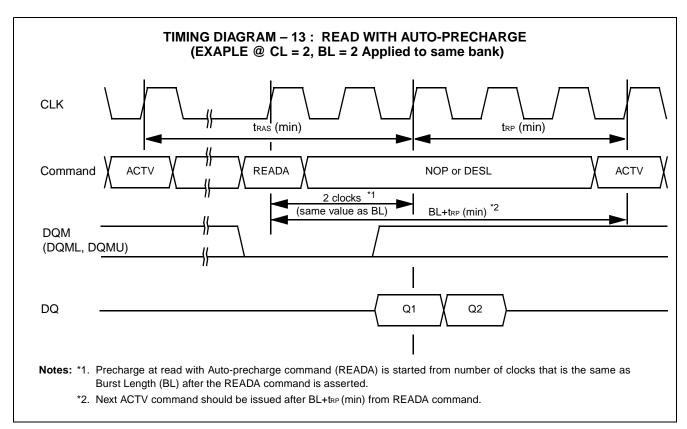


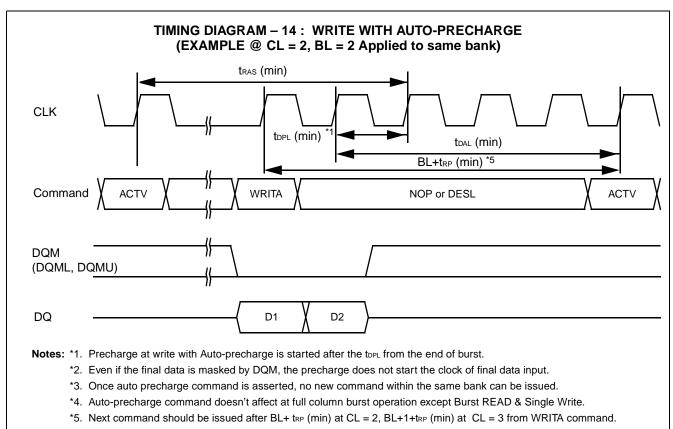


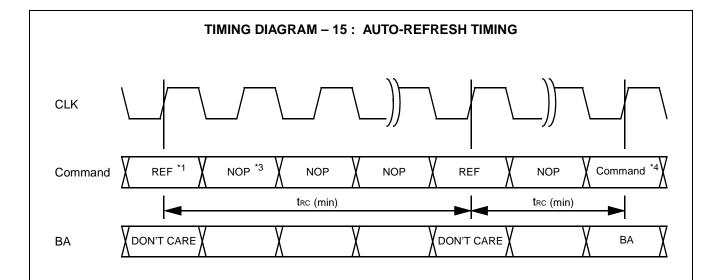






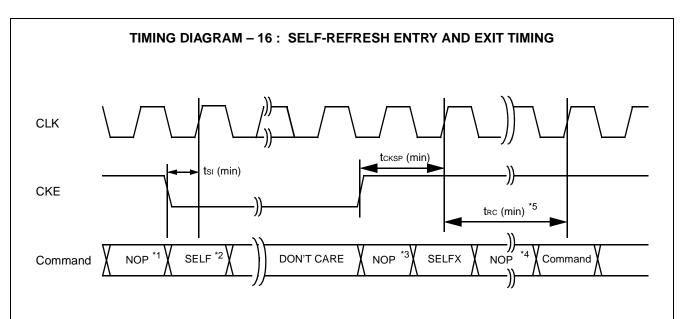




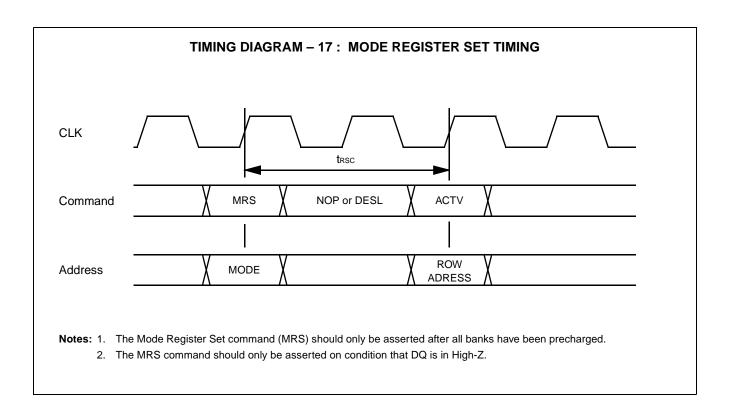


Notes: \*1. All banks should be precharged prior to the first Auto-refresh command (REF).

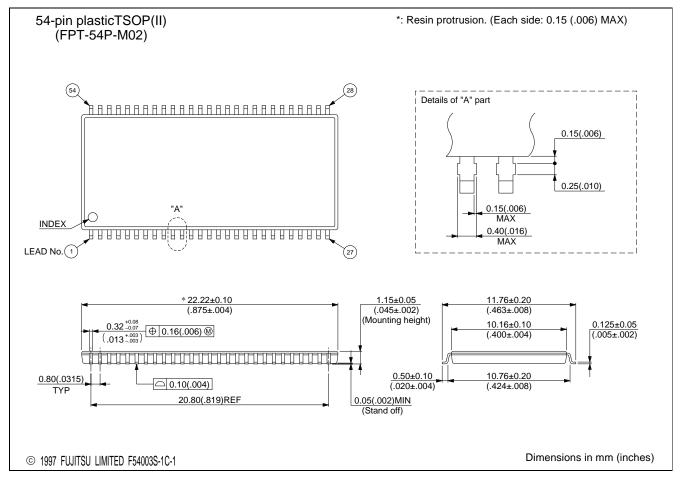
- \*2. Bank select is ignored at REF command. The refresh address and bank select are selected by internal refresh counter.
- \*3. Either NOP or DESL command should be asserted during tro period while Auto-refresh mode.
- \*4. Any activation command such as ACTV or MRS command other than REF command should be asserted after tec from the last REF comand.



- Notes: \*1. Precharge command (PRE or PALL) should be asserted if any bank is active prior to Self-refresh Entry command (SELF).
  - \*2. SELF command should be asserted after the last read data have been appeared on DQ.
  - \*3. The Self-refresh Exit command (SELFX) is latched after toksp (min). It is recommended to apply NOP command in conjunction with CKE.
  - $^{*}4$ . Either NOP or DESL command can be used during t<sub>RC</sub> period.
  - $^{\star}5.\,$  CKE should be held high within one tRC period after tcksr.



### **■ PACKAGE DIMENSION**



## **FUJITSU LIMITED**

For further information please contact:

#### Japan

**FUJITSU LIMITED** 

Corporate Global Business Support Division

**Electronic Devices** 

KAWASAKI PLANT, 4-1-1, Kamikodanaka

Nakahara-ku, Kawasaki-shi Kanagawa 211-8588, Japan

Tel: (044) 754-3763 Fax: (044) 754-3329

http://www.fujitsu.co.jp/

#### North and South America

FUJITSU MICROELECTRONICS, INC.

Semiconductor Division 3545 North First Street

San Jose, CA 95134-1804, USA

Tel: (408) 922-9000 Fax: (408) 922-9179

Customer Response Center Mon. - Fri.: 7 am - 5 pm (PST)

Tel: (800) 866-8608 Fax: (408) 922-9179

http://www.fujitsumicro.com/

#### **Europe**

FUJITSU MIKROELEKTRONIK GmbH Am Siebenstein 6-10 D-63303 Dreieich-Buchschlag Germany

Tel: (06103) 690-0 Fax: (06103) 690-122

http://www.fujitsu-ede.com/

#### **Asia Pacific**

FUJITSU MICROELECTRONICS ASIA PTE LTD #05-08, 151 Lorong Chuan

New Tech Park Singapore 556741 Tel: (65) 281-0770

Fax: (65) 281-0220

http://www.fmap.com.sg/

#### F9802

© FUJITSU LIMITED Printed in Japan

All Rights Reserved.

The contents of this document are subject to change without notice. Customers are advised to consult with FUJITSU sales representatives before ordering.

The information and circuit diagrams in this document presented as examples of semiconductor device applications, and are not intended to be incorporated in devices for actual use. Also, FUJITSU is unable to assume responsibility for infringement of any patent rights or other rights of third parties arising from the use of this information or circuit diagrams.

FUJITSU semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION:

Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with FUJITSU sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

If any products described in this document represent goods or technologies subject to certain restrictions on export under the Foreign Exchange and Foreign Trade Control Law of Japan, the prior authorization by Japanese government should be required for export of those products from Japan.